

| QUALIFICATION PLAN   |                                |                  |                          |
|--|--------------------------------|------------------|--------------------------|
| TEST   | CONDITIONS                     | SAMPLE SIZE      | EXPECTED COMPLETION DATE |
| High Temperature Operating Life (HTOL)*                              | JEDEC <i>JESD22-A108</i>       | <b>3x32</b>      | <b>Complete</b>          |
| Highly Accelerated Stress Test (HAST)*                               | JEDEC <i>JESD22-A110</i>       | <b>3x32</b>      | <b>Complete</b>          |
| Temperature Cycle (TC)*  | JEDEC <i>JESD22-A104</i>       | <b>3x32</b>      | <b>Complete</b>          |
| ELF  | MIL-STD-883, Method 1015       | <b>3x667</b>     | <b>Complete</b>          |
| Autoclave (AC)*  | JEDEC <i>JESD22-A102</i>       | <b>3x32</b>      | <b>Complete</b>          |
| High Temperature Storage Life (HTSL)                                 | JEDEC <i>JESD22-A103</i>       | <b>1x32</b>      | <b>Complete</b>          |
| Solder Heat Resistance (SHR)*  | <i>ADI-0049</i>                | <b>3x11</b>      | <b>Complete</b>          |
| Latch-Up   | JEDEC <i>JESD78</i>            | <b>6</b>         | <b>Complete</b>          |
| Electrostatic Discharge<br><i>Human Body Model</i>                   | ESDA/JEDEC <i>JDS-001-2011</i> | <b>3/voltage</b> | <b>Complete</b>          |
| Electrostatic Discharge<br><i>Field-Induced Charged Device Model</i> | JEDEC <i>JESD22-C101</i>       | <b>3/voltage</b> | <b>Complete</b>          |

\*Preconditioned per JEDEC/IPC J-STD-020